# CDCU877/CDCU877A 1.8-V PHASE LOCK LOOP CLOCK DRIVER

SCAS688A - JUNE 2003 - REVISED JANUARY 2004

- 1.8-V Phase Lock Loop Clock Driver for Double Data Rate (DDR II) Applications
- Spread Spectrum Clock Compatible
- Operating Frequency: 10 MHz to 400 MHz
- Low Current Consumption: <135 mA</li>
- Low Jitter (Cycle-Cycle): ±30 ps
- Low Output Skew: 35 psLow Period Jitter: ±20 ps
- Low Dynamic Phase Offset:: ±15 ps
   Low Static Phase Offset:: ±50 ps
- Distributes One Differential Clock Input to Ten Differential Outputs
- 52-Ball µBGA (MicroStar Junior™ BGA, 0.65-mm pitch) and 40-Pin MLF

- External Feedback Pins (FBIN, FBIN) are Used to Synchronize the Outputs to the Input Clocks
- Single-Ended Input and Single-Ended Output Modes
- Meets or Exceeds JESD82-8 PLL Standard for PC2-3200/4300
- Fail-Safe Inputs

#### description

The CDCU877 is a high-performance, low-jitter, low-skew, zero-delay buffer that distributes a differential clock input pair (CK,  $\overline{CK}$ ) to ten differential pairs of clock outputs (Yn,  $\overline{Yn}$ ) and to one differential pair of feedback clock outputs (FBOUT, FBOUT). The clock outputs are controlled by the input clocks (CK,  $\overline{CK}$ ), the feedback clocks (FBIN, FBIN), the LVCMOS control pins (OE, OS), and the analog power input (AV $_{DD}$ ). When OE is low, the clock outputs, except FBOUT/FBOUT, are disabled while the internal PLL continues to maintain its locked-in frequency. OS (output select) is a program pin that must be tied to GND or  $V_{\overline{DD}}$ . When OS is high, OE functions as previously described. When OS and OE are both low, OE has no affect on Y7/Y7, they are free running. When AV $_{DD}$  is grounded, the PLL is turned off and bypassed for test purposes.

When both clock inputs (CK,  $\overline{\text{CK}}$ ) are logic low, the device enters in a low power mode. An input logic detection circuit on the differential inputs, independent from input buffers, detects the logic low level and performs in a low power state where all outputs, the feedback, and the PLL are off. When the clock inputs transition from being logic low to being differential signals, the PLL turns back on, the inputs and the outputs are enabled, and the PLL obtains phase lock between the feedback clock pair (FBIN,  $\overline{\text{FBIN}}$ ) and the clock input pair (CK,  $\overline{\text{CK}}$ ) within the specified stabilization time.

The CDCU877 is able to track spread spectrum clocking (SSC) for reduced EMI. This device operates from –40°C to 85°C.

#### **AVAILABLE OPTIONS**

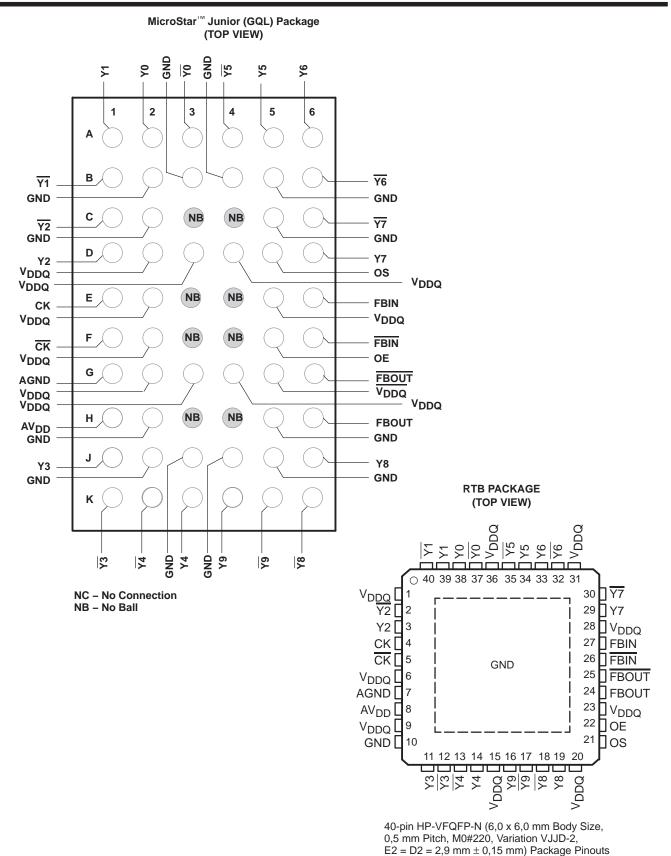
TA	52-Ball BGA	40-Pin MLF
-40°C to 85°C	CDCU877ZQL (Pb-Free)	CDCU877RTB
-40°C to 85°C	CDCU877AZQL (Pb-Free)	CDCU877ARTB
–40°C to 85°C	CDCU877GQL	
-40°C to 85°C	CDCU877AGQL	



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MicroStar Junior is a trademark of Texas Instruments.







**Table 1. Terminal Functions** 

NAME	BGA	MLF	I/O	DESCRIPTION
AGND	G1	7		Analog ground
$AV_{DD}$	H1	8		Analog power
CK	E1	4	Ι	Clock input with a (10 k $\Omega$ to 100 k $\Omega$ ) pulldown resistor
CK	F1	5	Ι	Complementary clock input with a (10 k $\Omega$ to 100 k $\Omega$ ) pulldown resistor
FBIN	E6	27	Ι	Feedback clock input
FBIN	F6	26	I	Complementary feedback clock input
FBOUT	H6	24	0	Feedback clock output
FBOUT	G6	25	0	Complementary feedback clock output
OE	F5	22	I	Output enable (asynchronous)
OS	D5	21	I	Output select (tied to GND or V <sub>DD</sub> )
GND	B2, B3, B4, B5, C2, C5, H2, H5, J2, J3, J4, J5	10		Ground
V <sub>DDQ</sub>	D2, D3, D4, E2, E5, F2, G2, G3, G4, G5	1, 6, 9, 15, 20, 23, 28, 31, 36		Logic and output power
Y[0:9]	A2, A1, D1, J1, K3, A5, A6, D6, J6, K4	38, 39, 3, 11, 14, 34, 33, 29, 19, 16	0	Clock outputs
Y[0:9]	A3, B1, C1, K1, K2, A4, B6, C6, K6, K5	37, 40, 2, 12, 13, 35, 32, 30, 18, 17	0	Complementary clock outputs

**Table 2. Function Table** 

INPUTS OUTPUTS						DLI			
AV <sub>DD</sub>	OE	os	CK	CK	Y	Y	FBOUT	FBOUT	PLL
GND	Н	Х	L	Н	L	Н	L	Н	Bypassed/ Off
GND	Н	Х	Н	L	Н	L	Н	L	Bypassed/ Off
GND	L	Н	L	Н	LZ	LZ	L	Н	Bypassed/ Off
GND	L	L	Н	L	L <sub>Z</sub> Y7 Active	LZ Y7 Active	Н	L	Bypassed/ Off
1.8 V Nominal	L	Н	L	Н	LZ	LZ	L	Н	On
1.8 V Nominal	L	L	Н	L	L <sub>Z</sub> Y7 Active	LZ Y7 Active	Н	L	On
1.8 V Nominal	Н	Х	L	Н	L	Н	L	Н	On
1.8 V Nominal	Н	Х	Н	L	Н	L	Н	L	On
1.8 V Nominal	Х	Х	L	L	LZ	LZ	LZ	LZ	Off
X	Х	Х	Н	Н	Reserved				

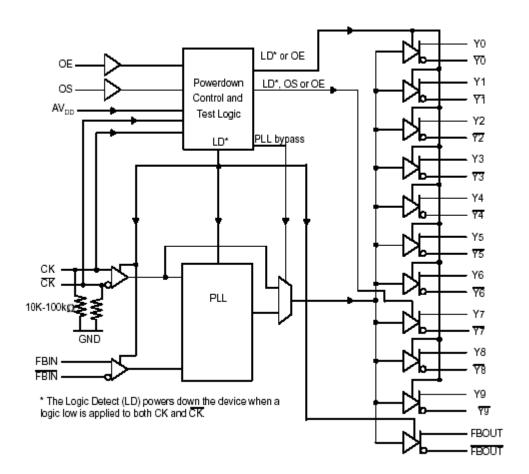


Figure 1. Logic Diagram (Positive Logic)



## absolute maximum ratings over operating free-air temperature (unless otherwise noted)†

Supply voltage range, V <sub>DDQ</sub> or AV <sub>DD</sub>	. $-0.5$ V to $2.5$ V
Input voltage range, V <sub>I</sub> (see Notes 1 and 2)	to $V_{DDQ} + 0.5 V$
Output voltage range, VO (see Notes 1 and 2)	to $V_{DDQ} + 0.5 V$
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{DDQ}$ )	±50 mA
Output clamp voltage, $I_{OK}$ ( $V_O < 0$ or $V_O > V_{DDQ}$ )	±50 mA
Continuous output current, I <sub>O</sub> (V <sub>O</sub> = 0 to V <sub>DDQ</sub> )	±50 mA
Continuous current through each V <sub>DDQ</sub> or GND	±100 mA
Storage temperature range, T <sub>STG</sub>	-65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### recommended operating conditions

			MIN	NOM	MAX	UNIT
$V_{DDQ}$	Output supply voltage		1.7	1.8	1.9	V
AV <sub>DD</sub>	Supply voltage	See Note 1		VDDQ		
VIL	Low-level input voltage (see Note 2)	OE, OS			$0.35 \times V_{DDQ}$	V
VIH	High-level input voltage (see Note 2)	CK, CK	$0.65 \times V_{DDQ}$			V
ЮН	High-level output current (see Figure 2			-9	mA	
lOL	Low-level output current (see Figure 2)				9	mA
V <sub>IX</sub>	Input differential-pair cross voltage		(V <sub>DDQ</sub> /2)-0.15		(V <sub>DDQ</sub> /2)+0.15	V
VI	Input voltage level		-0.3		V <sub>DDQ</sub> +0.3	V
VID	Input differential voltage	DC	0.3		V <sub>DDQ</sub> +0.4	V
	(see Note 2 and Figure 9)		0.6		V <sub>DDQ</sub> +0.4	V
TA	Operating free-air temperature		-40	•	85	°C

- NOTES: 1. The PLL is turned off and bypassed for test purposes when AV<sub>DD</sub> is grounded. During this test mode, V<sub>DDQ</sub> remains within the recommended operating conditions and no timing parameters are ensured.
  - 2. V<sub>ID</sub> is the magnitude of the difference between the input level on CK and the input level on CK, see Figure 9 for definition. The CK and CK V<sub>IH</sub> and V<sub>IL</sub> limits define the dc low and high levels for the logic detect state.



NOTES: 1. The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed

<sup>2.</sup> This value is limited to 2.5 V maximum.

#### electrical characteristics over recommended operating free-air temperature range

	PARAMETER		TEST CONDITIONS	AV <sub>DD</sub> , V <sub>DDQ</sub>	MIN	TYP	MAX	UNIT
VIK	Input (cl inputs)		I <sub>I</sub> = 18 mA	1.7 V			-1.2	V
Vон	High-level output voltage		I <sub>OH</sub> = -100 μA	1.7 V to 1.9 V	V <sub>DDQ</sub> - 0.2			V
011			I <sub>OH</sub> = -9 mA	1.7 V	1.1			
.,	Lave lavel autout valtage		I <sub>OL</sub> = 100 μA				0.1	
VOL	Low-level output voltage		I <sub>OL</sub> = 9 mA	1.7 V			0.6	V
I <sub>O(DL)</sub>	Low-level output current, disabled		$V_{O(DL)} = 100 \text{ mV}, OE = L$	1.7 V	100			μΑ
V <sub>OD</sub>	Differential output voltage (see Note 1)			1.7 V	0.5			V
		CK, CK		1.9 V			±250	
l <sub>l</sub>	Input current	OE, O <u>S,</u> FBIN, FBIN		1.9 V			±10	μΑ
I <sub>DD(LD)</sub>	Supply current, static (IDDQ	+ I <sub>ADD</sub> )	CK and CK = L	1.9 V			500	μΑ
I <sub>DD</sub>	Supply current, dynamic (Ippo + IAPP)		CK and CK = 270 MHz, All outputs are open (not connected to a PCB)	1.9 V			135	mA
			All outputs are loaded with 2 pF and 120-Ω termination resistor	1.9 V			235	
	land an alternati	CK, CK	V <sub>I</sub> = V <sub>DD</sub> or GND	1.8 V	2		3	
Cl	Input capacitance	FBIN, FBIN	V <sub>I</sub> = V <sub>DD</sub> or GND	1.8 V	2		3	pF
	Ohan and in install assess	CK, CK	V <sub>I</sub> = V <sub>DD</sub> or GND	1.8 V			0.25	
$C_{I(\Delta)}$	Change in input current	FBIN, FBIN	$V_I = V_{DD}$ or GND	1.8 V			0.25	pF

NOTES: 1. VOD is the magnitude of the difference between the true and complimentary outputs. See Figure 9 for a definition.

2. Total IDD = IDDQ + IADD = fCK × CPD × VDDQ, solving for CPD = (IDDQ + IADD)/(fCK × VDDQ) where fCK is the input frequency, VDDQ is the power supply, and CPD is the power dissipation capacitance.

#### timing requirements over recommended operating free-air temperature range

	PARAMETER	TEST CONDITIONS	MIN	TYP MAX	UNIT
fCK	Clock frequency (operating, see Notes 1 and 2)	$AV_{DD}$ , $V_{DD} = 1.8 \text{ V} \pm 0.1 \text{ V}$	10	400	MHz
fCK	Clock frequency (application, see Notes 1 and 3)	AV <sub>DD</sub> , V <sub>DD</sub> = 1.8 V ±0.1 V	160	340	MHz
t <sub>DC</sub>	Duty cycle, input clock	AV <sub>DD</sub> , V <sub>DD</sub> = 1.8 V ±0.1 V	40%	60%	
tL	Stabilization time (see Note 4)	AV <sub>DD</sub> , V <sub>DD</sub> = 1.8 V ±0.1 V		12	μs

NOTES: 1. The PLL must be able to handle spread spectrum induced skew.

- 2. Operating clock frequency indicates a range over which the PLL must be able to lock, but in which it is not required to meet the other timing parameters (used for low speed system debug).
- 3. Application clock frequency indicates a range over which the PLL must meet all timing parameters.
- 4. Stabilization time is the time required for the integrated PLL circuit to obtain phase lock of its feedback signal to its reference signal after power up. During normal operation, the stabilization time is also the time required for the integrated PLL circuit to obtain phase lock of its feedback signal to its reference signal when CK and CK go to a logic low state, enter the power-down mode and later return to active operation. CK and CK may be left floating after they have been driven low for one complete clock cycle.



#### switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Note 1)

 $AV_{DD}$ ,  $V_{DD} = 1.8 V \pm 0.1 V$ 

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
t <sub>en</sub>	Enable time, OE to any $Y/\overline{Y}$	See Figure 11			8	ns	
<sup>t</sup> dis	Disable time, OE to any $Y/\overline{Y}$	See Figure 11			8	ns	
tjit(cc+)	0 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1	100 1411 / 100 1411 - 5	0		40		
tjit(cc-)	Cycle-to-cycle period jitter (see Note 8)	160 MHz to 190 MHz, see Figure 4	0		-40	ps	
tjit(cc+)		400 MIL 4 0 40 MIL 5	0		30		
tjit(cc-)	Cycle-to-cycle period jitter (see Note 8)	190 MHz to 340 MHz, see Figure 4	0		-30	ps	
t <sub>(φ)</sub>	Static phase offset time (see Note 2)	See Figure 5	-50		50	ps	
t(φ)dyn	Dynamic phase offset time	See Figure 10	-15		15	ps	
tsk(o)	Output clock skew	See Figure 6			35	ps	
		160 MHz to 190 MHz, see Figure 7	-30		30	ps	
<sup>t</sup> jit(per)	Period jitter (see Notes 3 and 8)	190 MHz to 340 MHz, see Figure 7	-20		20	ps	
	Half-period jitter (see Notes 3 and 8)	160 MHz to 190 MHz, see Figure 8	-115		115	ps	
		190 MHz to 250 MHz, see Figure 8	-70		70	ps	
<sup>t</sup> jit(hper)		250 MHz to 300 MHz, see Figure 8	-40		40	ps	
		300 MHz to 340 MHz, see Figure 8	-60		60	ps	
	Slew rate, OE	See Figure 3 and Figure 9	0.5			V/ns	
SR	Input clock skew rate	See Figure 3 and Figure 9	1	2.5	4	V/ns	
SK	Output clock slew rate (see Notes 4 and 5)	See Figure 3 and Figure 9	1.5	2.5	3	V/ns	
	Output differential-pair cross voltage	See Figure 2, CDCU877	(V <sub>DDQ</sub> /2) - 0.1		(V <sub>DDQ</sub> /2) + 0.1		
VOX	(see Note 6)	See Figure 2, CDCU877A (see Note 7) (0–85°C)	(V <sub>DDQ</sub> /2) - 0.1		(V <sub>DDQ</sub> /2) + 0.1	V	
	SSC modulation frequency		30		33	kHz	
	SSC clock input frequency deviation		0%		-0.5%		
	PLL loop bandwidth		2			MHz	

- NOTES: 1. There are two different terminations that are used with the following tests. The load/board in Figure 2 is used to measure the input and output differential-pair cross voltage only. The load/board in Figure 3 is used to measure all other tests. For consistency, equal length cables must be used.
  - 2. Phase static offset time does not include jitter.
  - 3. Period jitter, half-period jitter specifications are separate specifications that must be met independently of each other.
  - 4. The output slew rate is determined from the IBIS model into the load shown in Figure 3.
  - 5. To eliminate the impact of input slew rates on static phase offset, the input skew rates of reference clock input CK and CK and feedback clock inputs FBIN and FBIN are recommended to be nearly equal. The 2.5-V/ns skew rates are shown as a recommended target. Compliance with these typical values is not mandatory if it can adequately shown that alternative characteristics meet the requirements of the registered DDR2 DIMM application.
  - 6. Output differential-pair cross voltage specified at the DRAM clock input or the test load.
  - 7. VOX of CDCU877A is on average 30 mV lower than that of CDCU877 for the same application.
  - 8. This parameter is assured by design and characterization.



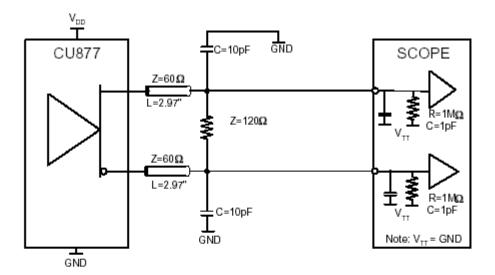


Figure 2. Output Load Test Circuit 1

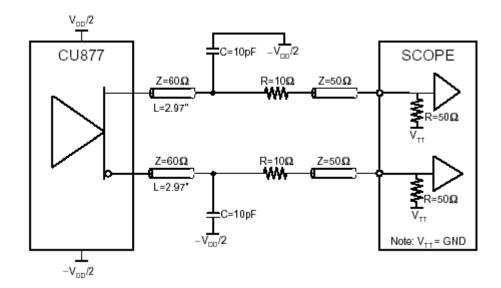


Figure 3. Output Load Test Circuit 2

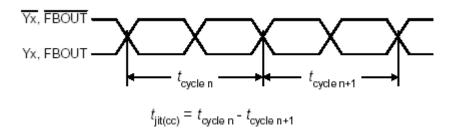
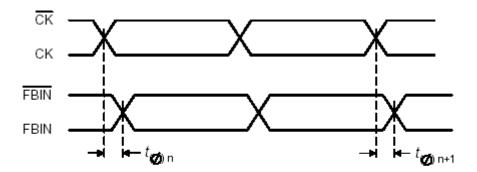


Figure 4. Cycle-To-Cycle Period Jitter





$$t_{00} = \frac{\sum_{1}^{n=N} t_{00} n}{N}$$
(N is a large number of samples)

(N>1000 samples)

Figure 5. Static Phase Offset

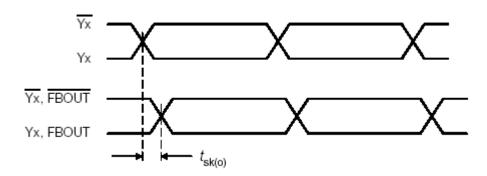
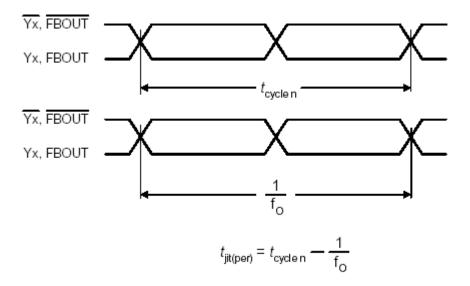
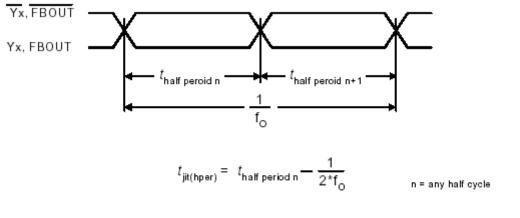


Figure 6. Output Skew



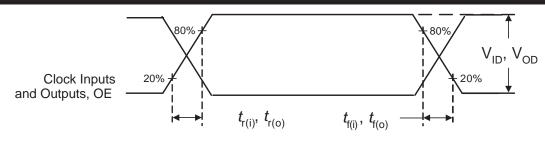
 $(f_O = average input frequency measured at CK/\overline{CK})$ 

Figure 7. Period Jitter



(fo = average input frequency measured at CK/CK)

Figure 8. Half-Period Jitter



$$strr_{(i/o)} = \frac{V_{80\%} - V_{20\%}}{t_{r(i/o)}}$$
  $strf_{(i/o)} = \frac{V_{80\%} - V_{20\%}}{t_{f(i/o)}}$ 

Figure 9. Input and Output Slew Rates

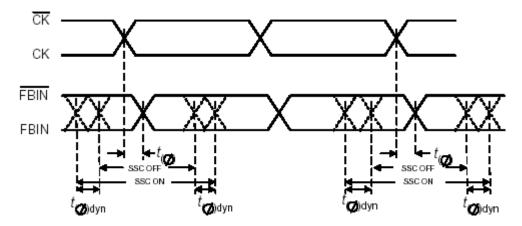


Figure 10. Dynamic Phase Offset

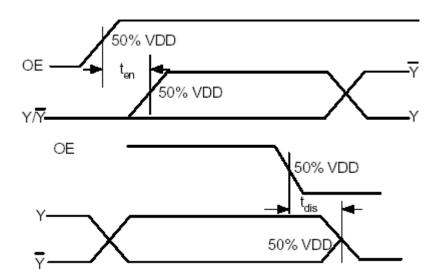
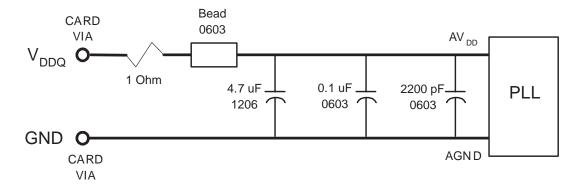


Figure 11. Time Delay Between OE and Clock Output  $(Y, \overline{Y})$ 

### RECOMMENDED AVDD FILTERING



See Notes 9, 10, and 11

Figure 12. Recommended  $AV_{DD}$  Filtering

NOTES: 9. Place the 2200-pF capacitor close to the PLL.

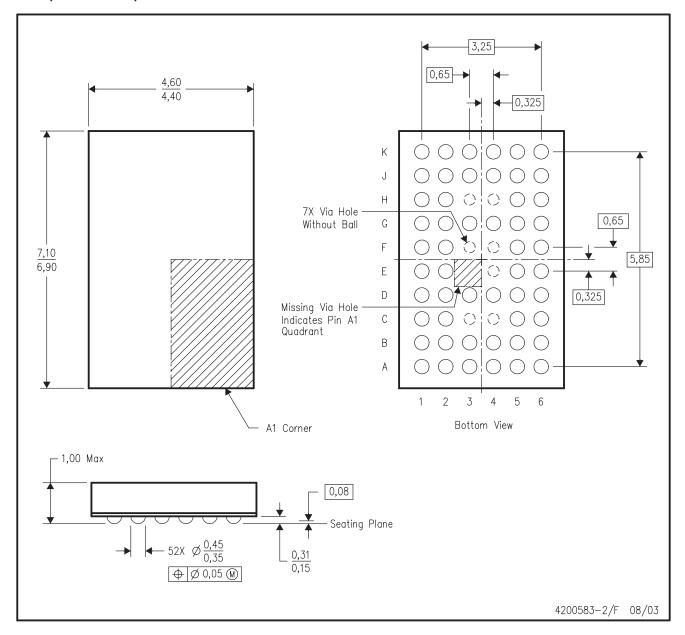
- 10. Use a wide trace for the PLL analog power and ground. Connect PLL and capacitors to AGND trace and connect trace to one GND via (farthest from the PLL).
- 11. Recommended bead: Fair-Rite PN 2506036017Y0 or equilvalent (0.8  $\Omega$  dc maximum, 600  $\Omega$  at 100 MHz).



#### **MECHANICAL DATA**

### GQL (R-PBGA-N52)

#### PLASTIC BALL GRID ARRAY



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. MicroStar Junior™ BGA configuration
- D. Falls within JEDEC MO-225 variation BA.
- E. This package is tin-lead (SnPb).

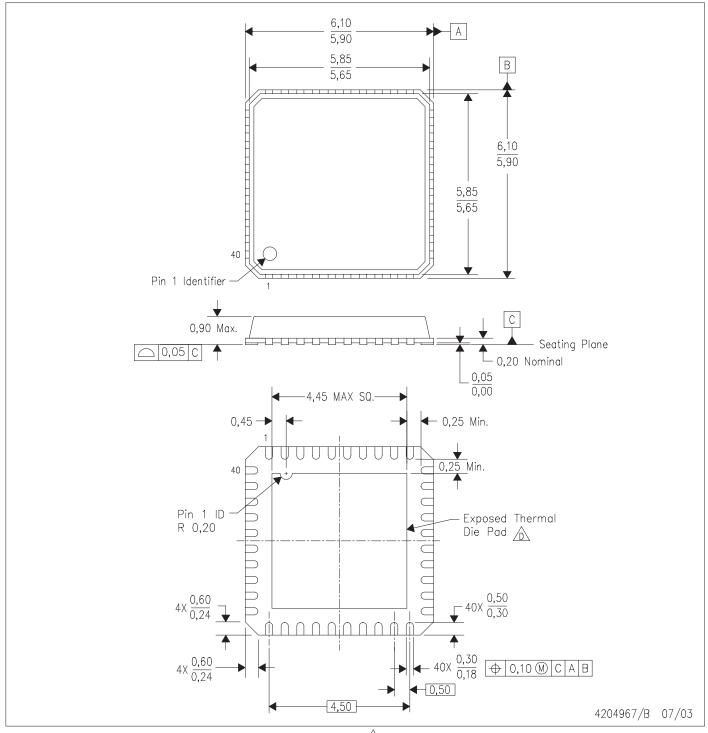
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#### **MECHANICAL DATA**

### RTB (S-PQFP-N40)

#### PLASTIC QUAD FLATPACK



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. QFN (Quad Flatpack No-Lead) package configuration.

The Package thermal performance may be enhanced by bonding the thermal die pad to an external thermal plane.

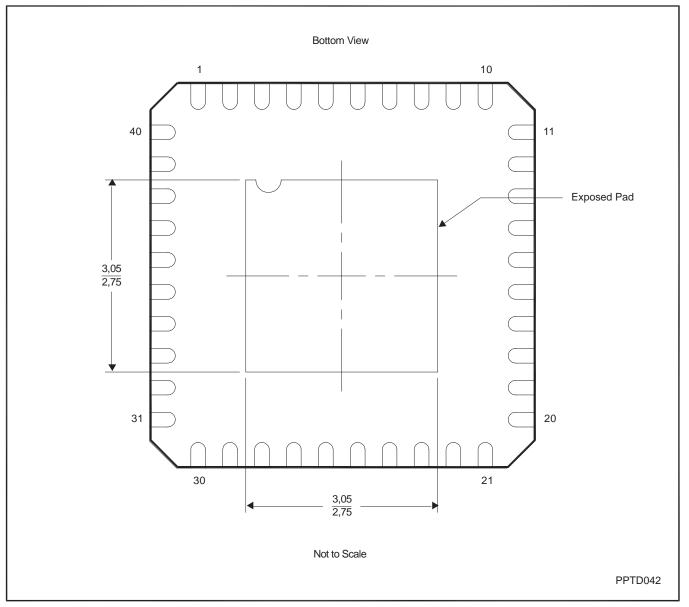
This sad may be electrically connected to ground.



#### THERMAL PAD MECHANICAL DATA

### RTB (S-PQFP-N40)

#### **PLASTIC QUAD FLATPACK**



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. QFN (Quad Flatpack No-Lead) Package configuration.

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